## Search Notes



## Application/Control No.

10532524

Applicant(s)/Patent Under Reexamination

CHEN ET AL.

Examiner

Emmanuel Bayard

**Art Unit** 

2611

## **SEARCHED**

Class	Subclass	Date	Examiner		
375	316, 340, 341, 324	6/4/2008	EB		

SEV	D	$\sim$ H	NC	<b>TES</b>
OE#	١ĸ١	υп	INC	ノIEO

Search Notes	Date	Examiner
East	6/4/2008	EB

## **INTERFERENCE SEARCH**

Class	Subclass	Date	Examiner
375	316, 340	6/4/2008	EB

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